


<b>Search Notes</b>  	<b>Application/Control No.</b>  10802927	<b>Applicant(s)/Patent Under Reexamination</b>  NAKANO ET AL.
	<b>Examiner</b>  JASON K GEE	<b>Art Unit</b>  2434

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
713	192	1/12/2009	JKG

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST - US PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	1/12/2009	JKG
PALM - Inventor Name Search	1/12/2009	JKG

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

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